

Product Change Notice

Issue Date: 15-Feb-2022
 Updated: 24-Jun-2022
 Updated: 14-Sep-2022
 Updated: 18-Jan-2023

Change Description:

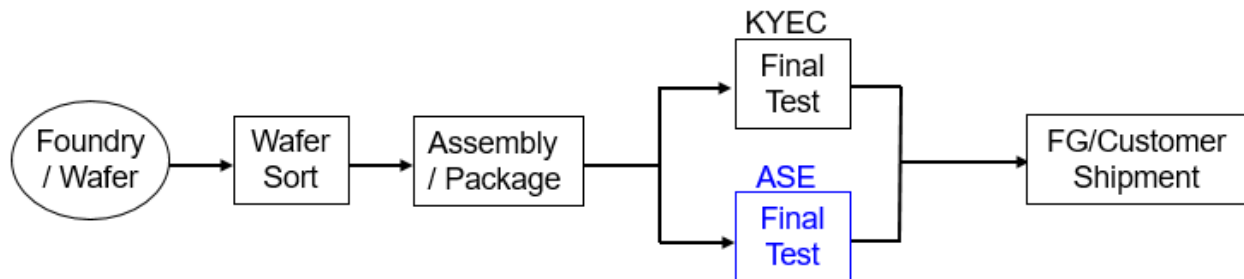
Add ASE-M as a 2nd source Final Test site

Parts Affected:

- BCM89830A0BWMGLT
- BCM89830A0BWMGLG
- BCM89832A0BWMGLT
- BCM89832A0BWMGLG

Description and Extent of Change:

Electrical Final Testing (FT) is currently performed on this product at KYEC (Chu-Nan, Taiwan R.O.C.). Broadcom will add ASE (Malaysia) as a 2nd source for FT. There is no change to the Foundry, Wafer Sort, or Assembly locations or processes – see updated flow below.



Note that ASE-M is a Broadcom qualified automotive supplier.

Reasons for Change:

Increase final test capacity and flexibility

Effect of Change on Fit, Form, Function, Quality, or Reliability:

The device specification, test limits, SYA/SBL limits, and S-PAT will remain the same, which will ensure product electrical performance remains the same. Appropriate correlation was performed to ensure no impact on Fit, Form, Function, Quality, or Reliability.

Effective Date of Change:

Product shipments using this change will begin after the dates shown in the table below. Timing of shipment of parts tested at ASE-KH will vary by part number depending on customer demand and inventory levels.

Part Number	Earliest Ship Date
BCM89832	31-Oct-2022
BCM89830	31-Jan-2023

Correlation Information:

The KYEC-to-ASE correlation has been completed.

Part Number	Correlation Date
BCM89832	Complete
BCM89830	Complete

See the table below for correlation details. These devices use the same silicon die and package type (WQFN).

Correlation Item	ASE Final Test			
	BCM89832		BCM89830	
Tester	Same as at KYEC		Same as at KYEC	
Test DIB	Same as at KYEC		Same as at KYEC	
Test Program	Same as at KYEC		Same as at KYEC	
Test time / # of tests	Same as at KYEC		Same as at KYEC	
SYL/SBL limits	Same as at KYEC		Same as at KYEC	
S-PAT limits	Same as at KYEC		Same as at KYEC	
	Result	OK/NOK	Result	OK/NOK
Tester MSA	Pass	OK	Pass	OK
Reproducibility: - Loop 20x; 4 units/site (4 sites) @ Hot Temp - Loop 20x; 4 units/site (4 sites) @ Cold Temp	Hot Temp: 320/320 Pass Cold Temp: 320/320 Pass	OK	Hot Temp: 320/320 Pass Cold Temp: 320/320 Pass	OK
Repeatability: - Loop 50x; 1 unit @ Hot Temp - Loop 50x; 1 unit @ Cold Temp	Hot Temp: 50/50 Pass Cold Temp: 50/50 Pass	OK	Hot Temp: 50/50 Pass Cold Temp: 50/50 Pass	OK
Yield/reject correlation/comparison (≥25 KGU & ≥25 KBU)*	Hot Temp: KGU 25/25 Pass; KBU 0/25 Pass Cold Temp: KGU 25/25 Pass; KBU 0/25 Pass	OK	Hot Temp: KGU 25/25 Pass; KBU 0/25 Pass Cold Temp: KGU 25/25 Pass; KBU 0/25 Pass	OK
Analog test parameter correlation (500u/lot)	3 lots		3 lots	
		OK		OK

*Note: KGU = Known Good Units; KBU = Known Bad Units

Please contact your Broadcom field sales engineer or Contact Center for any questions or support requirements. Please return any response as soon as possible, but **not to exceed 30 days**.